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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

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Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	6144
Total RAM Bits	36864
Number of I/O	60
Number of Gates	250000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-20°C ~ 85°C (TJ)
Package / Case	81-WFBGA, CSBGA
Supplier Device Package	81-CSP (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/agln250v2-csg81

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

User Nonvolatile FlashROM

IGLOO nano devices have 1 kbit of on-chip, user-accessible, nonvolatile FlashROM. The FlashROM can be used in diverse system applications:

- Internet protocol addressing (wireless or fixed)
- System calibration settings
- Device serialization and/or inventory control
- Subscription-based business models (for example, set-top boxes)
- · Secure key storage for secure communications algorithms
- Asset management/tracking
- Date stamping
- Version management

The FlashROM is written usinghe standard IGLOO nano IEEE 1532/TAG programming interface. The core can be individually programmed (erased anvalitten), and on-chip AES decryption can be used selectively to securely load data over public netwoo(except in the AGLN030 and smaller devices), as in security keys stored in the FlashROM for a user design.

The FlashROM can be programmed via the JTAG programming interface, and its contents can be read back either through the JTAG programming interface/iardirect FPGA core addressing. Note that the FlashROM can only be programmed from the JTAG terface and cannot be programmed from the internal logic array.

The FlashROM is programmed as 8 banks of 128 bits wever, reading is performed on a byte-by-byte basis using a synchronous interface. A 7-bit addressift the FPGA core defines which of the 8 banks and which of the 16 bytes within that bank are beinegd. The three most significant bits (MSBs) of the FlashROM address determine the bank, and the foleast significant bits (LSBs) of the FlashROM address define the byte.

The IGLOO nano development software solutions, Libe Soystem-on-Chip (SoC) and Designer, have extensive support for the FlashROM. One such feat is auto-generation of sequential programming files for applications requiring a unique serial number part. Another feature enables the inclusion of static data for system version control. Data for the FlashROM can be generated quickly and easily using Microsemi Libero SoC and Designer software tools. Comprehensive programming file support is also included to allow for easy programming of large numbers of parts with differing FlashROM contents.

SRAM and FIFO

IGLOO nano devices (except the AGLN030 and smaller devices) have embedded SRAM blocks along their north and south sides. Each variable-aspecter a BiRAM block is 4,608 bits in size. Available memory configurations ar 256 ± 8,5129, 1k ± 2k ± and 4k ± bits. The individual blocks have independent read and write ports that can be cgurfied with different bit widths on each port. For example, data can be sent through a 4-bit point read as a single bitstream. The embedded SRAM blocks can be initialized via the device JTAP fort (ROM emulation mode) using the UJTAG macro (except in the AGLN030 and smaller devices).

In addition, every SRAM block has an embedded FED control unit. The controunit allows the SRAM block to be configured as a synchronous FIFO with using additional core VersaTiles. The FIFO width and depth are programmable. The FIFO also fearles programmable Almost Empty (AEMPTY) and Almost Full (AFULL) flags in addition to the norman programmable for generation of the read and write address pointers. The embedded SRAM/FIFO blocks can be cascaded create largerconfigurations.

PLL and CCC

Higher density IGLOO nano devices integ either the two I/O bank or four I/O bank architectures provide designers with very flexible clock conditioning **bailities**. AGLN060, AGLN25, and AGLN250 contain six CCCs. One CCC (center west side) has a PLII AGLN030 and smaller devices use different CCCs in their architecture (CCC-GL). These CCC-GL contain a global MUX but do not have any PLLs or programmable delays.

For devices using the six CCC block architecture, **these** located at the four corners and the centers of the east and west sides. All six CCC blocks arealose; the four cornerCCCs and the east CCC allow simple clock delay operations areal as clock spine access.

Applies to 1.2 V DC Core Voltage

	Commerc	ial-Case Co	JIIUIUUIS	. I J=	- 70 C,	100151-		C = 1.14	+ v, vvc	Jist-Ca		-1 = 2.7	v
Drive Strength	Equivalent Software Default Drive Strength Option ¹	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{PYS}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	Units
100 µA	2 mA	STD	1.55	6.01	0.26	1.31	1.91	1.10	6.01	5.66	3.02	3.49	ns
100 µA	4 mA	STD	1.55	6.01	0.26	1.31	1.91	1.10	6.01	5.66	3.02	3.49	ns
100 µA	6 mA	STD	1.55	5.02	0.26	1.31	1.91	1.10	5.02	4.76	3.38	4.10	ns
100 µA	8 mA	STD	1.55	5.02	0.26	1.31	1.91	1.10	5.02	4.76	3.38	4.10	ns

Table 2-43 •3.3 V LVCMOS Wide Range Low Slew– Applies to 1.2 V DC Core Voltage
Commercial-Case Conditions: TJ = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.7 V

Notes:

 The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is ±100 μA. Drive strength displayed in the software is supported for normal range only. For a detailed I/V curve, refer to the IBIS models.

2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Table 2-44 • 3.3 V LVCMOS Wide Range High Slew – Applies to 1.2 V DC Core VoltageCommercial-Case Conditions: TJ = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.7 V

Drive Strength	Equivalent Software Default Drive Strength Option ¹	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{PYS}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	Units
100 µA	2 mA	STD	1.55	3.82	0.26	1.31	1.91	1.10	3.82	3.15	3.01	3.65	ns
100 µA	4 mA	STD	1.55	3.82	0.26	1.31	1.91	1.10	3.82	3.15	3.01	3.65	ns
100 µA	6 mA	STD	1.55	3.25	0.26	1.31	1.91	1.10	3.25	2.61	3.38	4.27	ns
100 µA	8 mA	STD	1.55	3.25	0.26	1.31	1.91	1.10	3.25	2.61	3.38	4.27	ns

Notes:

 The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is ±100 μA. Drive strength displayed in the software is supported for normal range only. For a detailed I/V curve, refer to the IBIS models.

2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

3. Software default selection highlighted in gray.



IGLOO nano DC and Switching Characteristics

Global Tree Timing Characteristics

Global clock delays include the central rib delay, the spine delay, and the row delay. Delays do not include I/O input buffer clock delays, as these are I/O standard–dependent, and the clock may be driven and conditioned internally by the CCC module. For more details on clock conditioning capabilities, refer to the Clock Conditioning Circuits"section on page 2-70 able 2-88 to Table 2-96 on page 2-68 present minimum and maximum global clock delays within each device. Minimum and maximum delays are measured with minimum and maximum loading.

Timing Characteristics

1.5 V DC Core Voltage

Table 2-88 • AGLN010 Global Resource Commercial-Case Conditions: T _1 = 70°C, VCC = 1.425 V

		5	Std.		
Parameter	Description	Min. ¹	Max. ²	Units	
t _{RCKL}	Input Low Delay for Global Clock	1.1	3 1.42	ns	
^t кскн	Input High Delay for Global Clock	1.1	5 1.50	ns	
t _{RCKMPWH}	Minimum Pulse Width HIGH for Global Clock	1.4	0	ns	
t _{RCKMPWL}	Minimum Pulse Width LOW for Global Clock	1.6	5	ns	
t _{RCKSW}	Maximum Skew for Global Clock		0.35	ns	

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).

2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).

3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Std. Parameter Min.¹ Max.² Units Description Input Low Delay for Global Clock 1.21 1.55 ns **t_{RCKL}** Input High Delay for Global Clock 1.23 1.65 t_{RCKH} ns Minimum Pulse Width HIGH for Global Clock 1.40 ns ^tRCKMPWH Minimum Pulse Width LOW for Global Clock 1.6 ns Maximum Skew for Global Clock 0.42 ns **t**RCKSW

Table 2-89 •AGLN015 Global ResourceCommercial-Case Conditions: TJ = 70°C, VCC = 1.425 V

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).

2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).

3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.



IGLOO nano DC and Switching Characteristics

VersaTile Specifications as a Sequential Module

The IGLOO nano library offers a wide variety of sequential cells, including flip-flops and latches. Each has a data input and optional enable, clear, or preset. In this section, timing characteristics are presented for a representative sample from the library. For more details, refer to the *IGLOO*, *ProASIC3*, *SmartFusion and Fusion Macro Library Guide for Software v10.1*.

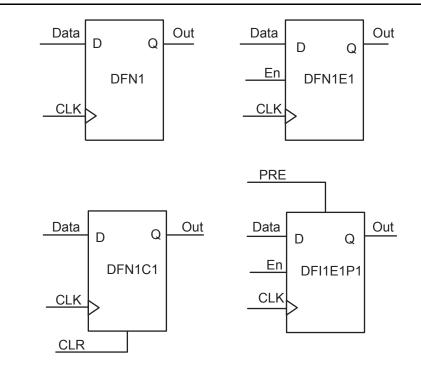


Figure 2-23 • Sample of Sequential Cells